



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

CONTECH RESEARCH INC.  
67 Mechanic Street  
Attleboro, MA 02703  
Mark Gates 508 226 4800

ELECTRICAL

Valid To: February 28, 2014

Certificate Number: 1478.02

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following tests on aerospace, aircraft, automotive, and computer components, cable assemblies, connectors and interconnect systems; commercial and military:

<u>Test</u>	<u>Test Method(s)</u>
<b>Resistance Parameters</b>	<b>(1 to 100) ma @ 20mv DC OC, 1 ma to 600 ADC</b>
LLCR Manual, Semi-Automatic and Automatic	EIA 364 TP 23; MIL-STD-1344 Method 3002; MIL-STD-55302; IEC 512, 2-1 USB 2.0; SAE/USCAR-2; SAE/USCAR-30; IEEE 1394
Contact Resistance	EIA 363 TP 06; MIL-STD-1344 Method 3004; MIL-STD-202 Method 307; IEC 512, 2-2; IEEE 1394
Voltage Drop	SAE/USCAR-2
<b>RF Parameters</b>	<b>300 KHz to 6 GHz @ 50 Ω 300 KHz to 2 GHz @ 75 Ω DC to 20 GHz, 1 ps</b>
VSWR	EIA 364 TP 108; IEC 512 Test 25e
Attenuation	EIA 364 TP 101; USB 2.0; SAE/USCAR-30; IEEE 1394

<b><u>Test</u></b>	<b><u>Test Method(s)</u></b>
Propagation Delay	EIA 364 TP 103; USB 2.0; SAE/USCAR-30; IEEE 1394
Crosstalk	EIA 364 TP 90; IEEE 1394
Risetime Degredation	EIA 364 TP 102
RF Hi Pot Withstanding Voltage	MIL-PRF-39012
Impedance	EIA 364 TP 108; USB 2.0; SAE/USCAR-30; IEEE 1394
<b>Parameters</b>	
	<b>1 KHz to 1 GHz</b>
Inductance	EIA 364 TP 33, TP 69
Capacitance	EIA 364 TP 30; MIL-STD-202 Method 305; IEC 512, 22-1; USB 2.0
<b>Detection Parameters</b>	
	<b>1ns, 10 ns, 50ns, .1µs, 1 µs, 10µs</b>
Low Nanosecond Event Detection	EIA 364 TP 87
Discontinuity Event Detection	EIA 364 TP46; MIL-STD-202 Method 310; IEC 512, 2-5; IEEE 1394
<b>DWV Parameters</b>	
	<b>300 V to 5000 VAC, Up to 4 mbars</b>
DWV Sea Level	EIA364 TP 20; MIL-STD-1344 Method 3001; MIL-STD-202 Method 301; UL 1977; IEC 512, 4-1; USB 2.0; IEEE 1394
DWV Altitude	EIA 364 TP 20; IEC 512, 4-1

<b>Test</b>	<b>Test Method(s)</b>
<b>IR Parameters</b>	<b>100 VDC to 1000 VDC, 50,000 Megohms Max</b>
Insulation Resistance	EIA 364 TP 21; MIL-STD-1344 Method 3003; MIL-STD-202 Method 302; IEC 512, 3-1; USB 2.0; SAE/USCAR-2; SAE/USCAR-30; IEEE 1394
<b>Parameters</b>	<b>100 mA to 600ADC</b>
Current Cycling	EIA 364 TP 55; IEC 512, 9-5; SAE/USCAR-2
Temperature Rise	EIA 364 TP 70; UL1977; IEC 512, 5-1, 5-2; SAE/USCAR-2
<b>Parameters</b>	<b>100 mA to 600ADC, 1V to 100 VDC</b>
Current Overload (Hot Swap)	UL 1977
Resistance to Arcing	UL 1977

\*Also customer specific test methods utilizing any combination of test equipment parameters listed above.



The American Association for Laboratory Accreditation

World Class Accreditation

# Accredited Laboratory

A2LA has accredited

## CONTECH RESEARCH INC.

*Attleboro, MA*

for technical competence in the field of

### Electrical Testing

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 *General Requirements for the Competence of Testing and Calibration Laboratories*. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (*refer to joint ISO-ILAC-IAF Communiqué dated 8 January 2009*).

Presented this 6<sup>th</sup> day of April 2012.



  
\_\_\_\_\_  
Peter Abney

President & CEO  
For the Accreditation Council  
Certificate Number 1478.02  
Valid to February 28, 2014

*For the tests or types of tests to which this accreditation applies, please refer to the laboratory's Electrical Scope of Accreditation.*